

Critical behaviour of resistivity in dilute ferromagnetic semiconductors

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One of the open questions in the physics of conducting magnets is the origin of the critical behaviour of resistivity at the Curie temperature. In $\text{Ga}_{1-x}\text{Mn}_x\text{As}$ that has become an archetypical carrier-mediated dilute ferromagnetic semiconductor, a phenomenological approach showed that the singularity in dR/dT at T_C can be consistently interpreted in terms of large wave vector scattering of hole carriers by Mn spin fluctuations [1]. However, it is known that spin-disorder scattering affects resistance also *via* quantum localisation corrections to conductivity in a disordered systems [2]. In this work we examine the role of this effect across the paramagnet-ferromagnet phase transition. Within this approach we find a semi-quantitative agreement between our experimental and theoretical results. Furthermore, to tell the relative importance of one-electron compared to Coulomb correlation effects we extend our analysis to $(\text{Pb}_{1-x-y}, \text{Sn}_y, \text{Mn}_x)\text{Te}$. Being at the edge of the ferroelectricity this compound exhibits a high dielectric constant which modifies the nature of the disorder modified electron-electron interactions [3].

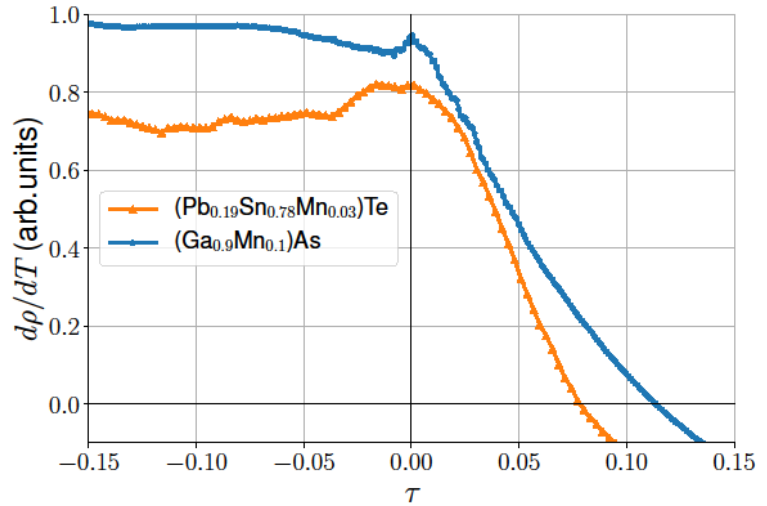


Fig 1. Temperature derivative of the measured resistivity of $\text{Ga}_{0.9}\text{Mn}_{0.1}\text{As}$ and $(\text{Pb}_{0.19}, \text{Sn}_{0.78}, \text{Mn}_{0.03})\text{Te}$ without an external magnetic field, where τ is a relative temperature distance to T_C .

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